	I I I			, !
QUERY CONTROL FORM		1 1	RTIS USE ON	ILY
Application No. 10/047135	Prepared by	H. Connelly	Tracking Number DOO	03341
Examiner-GAU JONES -	3736 Date	9/10/04	Week Date 81	30/04
	No. of queries	\mathcal{T}	Reuse-10	
			TEN	

JACKET						
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	PTO-1449			
b. Applicant(s)	g. Disclaimer	I. Print Fig.	q. PTOL-85b			
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract			
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs			
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other			

SPECIFICATION	message flegse either initial or line through citation. Copy provided for reference.
a. Page Missing	citation
b. Text Continuity	COM privided for reference.
c. Holes through Data	
d. Other Missing Text	
e. Illegible Text	
f. Duplicate Text	
g. Brief Description	
h. Sequence Listing	
i. Appendix	•
j. Amendments	
k. Other	
CLAIMS	
a. Claim(s) Missing	
b. Improper Dependency	
c. Duplicate Numbers	Thanks
d. Incorrect Numbering	initials APC
e. Index Disagrees	RESPONSE
f. Punctuation	
g. Amendments	
h. Bracketing	
i. Missing Text	
j. Duplicate Text	
k. Other	
	initials

Date: July 1, 2004

Page 1 of 1

					Date: July 1, 200	J~ 4	Page	1 01 1	
FORM PTO-1449 (Colb)		ATTY DOCKET NO. B00250.70010.US		SERIAL NUMBER 10/047,135					
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STRUCMENT			APPLICANT Yossi GROSS, et al. FILING DATE January 15, 2002		EXAMINER Brian Szmal GROUP ART UNIT 3736				
Examiner's Initials		DOCUMENT NO.	DAT	E	NAME .	CLASS	s s	UB	FILING DATE
	AA	6,061,596	05-200	0	Richmond, et al.			•	
	AB	6,735,474	05-200	4	Loeb, et al.		·		
	AC	2002/0055761	05-2002 01-2003		Mann, et al.				
	AD	2003/0018365			Loeb				
	ΑE	2004/0059392	03-200	4	Parramon, et al.				
	AF								
	AG								
	AH								•
			FOREIG	N PA	TENT DOCUMENTS				
-		DOCUMENT NO.	DAT	Œ	COUNTRY	CLAS	s s	SUB	TRANS- LATION
	AI								
	AJ			_					
	AK					1			
		OTHER A	ART (Inclu	ding	Author, Bills, Pertinent P	ages, Etc.)			
	AL								
	AM		٠		·				
EXAMIN	ER:			DA	TE CONSIDERED:				·
EXAMIN	60	9; Draw line thro	ugh citat	tion	nether or not citation if not in conforman unication to applican	ce and n	onform ot con	ance sidere	with MPE ed. Includ